

Notice of References Cited	Application/Control No. 10/751,418	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner EDMUND H. LEE	Art Unit 1732	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,521,158	02-2003	Ichikawa et al.	264/251
	C	US-			
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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